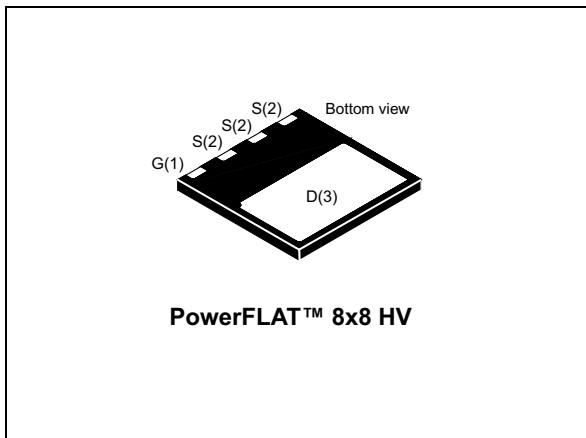
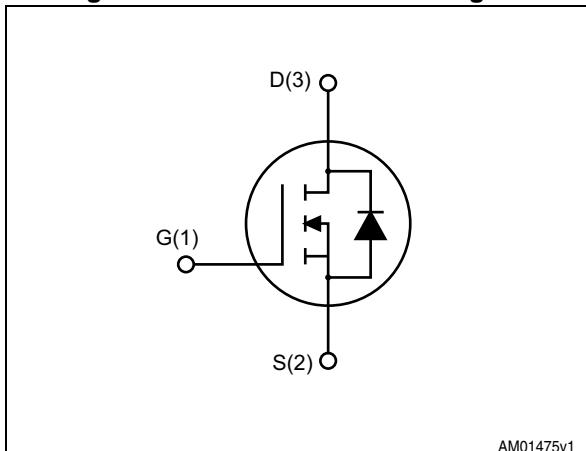


# N-channel 600 V, 0.26 $\Omega$ typ., 12 A MDmesh™ II Power MOSFET in a PowerFLAT™ 8x8 HV package

Datasheet - production data



**Figure 1. Internal schematic diagram**



## Features

Order code	V <sub>DS</sub> @ T <sub>Jmax</sub>	R <sub>DS(on)</sub> max	I <sub>D</sub>
STL18NM60N	650 V	0.310 $\Omega$	12 A (1)

1. The value is rated according to R<sub>thj-case</sub>

- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

## Applications

- Switching applications

## Description

This device is an N-channel Power MOSFET developed using the second generation of MDmesh™ technology. This revolutionary Power MOSFET associates a vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the most demanding high efficiency converters.

**Table 1. Device summary**

Order code	Marking	Packages	Packaging
STL18NM60N	18NM60N	PowerFLAT™ 8x8 HV	Tape and reel

## Contents

<b>1</b>	<b>Electrical ratings</b>	<b>3</b>
<b>2</b>	<b>Electrical characteristics</b>	<b>4</b>
2.1	Electrical characteristics (curves)	6
<b>3</b>	<b>Test circuits</b>	<b>8</b>
<b>4</b>	<b>Package mechanical data</b>	<b>9</b>
<b>5</b>	<b>Packaging mechanical data</b>	<b>13</b>
<b>6</b>	<b>Revision history</b>	<b>15</b>

# 1 Electrical ratings

**Table 2. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-source voltage	600	V
$V_{GS}$	Gate-source voltage	$\pm 30$	V
$I_D^{(1)}$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	12	A
$I_D^{(1)}$	Drain current (continuous) at $T_C = 100^\circ\text{C}$	7.5	A
$I_D^{(2)}$	Drain current (continuous) at $T_{amb} = 25^\circ\text{C}$	2.1	A
$I_D^{(2)}$	Drain current (continuous) at $T_{amb} = 100^\circ\text{C}$	1.2	A
$I_{DM}^{(2),(3)}$	Drain current (pulsed)	8.4	A
$P_{TOT}^{(2)}$	Total dissipation at $T_{amb} = 25^\circ\text{C}$	3	W
$P_{TOT}^{(1)}$	Total dissipation at $T_C = 25^\circ\text{C}$	110	W
$I_{AR}$	Avalanche current, repetitive or not-repetitive (pulse width limited by $T_j$ max)	4.5	A
$E_{AS}$	Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50\text{ V}$ )	350	mJ
$dv/dt^{(4)}$	Peak diode recovery voltage slope	15	V/ns
$T_{stg}$	Storage temperature	- 55 to 150	$^\circ\text{C}$
$T_j$	Max. operating junction temperature	150	$^\circ\text{C}$

1. The value is rated according to  $R_{thj-case}$
2. When mounted on 1inch<sup>2</sup> FR-4 board, 2 oz Cu
3. Pulse width limited by safe operating area
4.  $I_{SD} \leq 12\text{ A}$ ,  $di/dt \leq 400\text{ A}/\mu\text{s}$ ,  $V_{DSpeak} \leq V_{(BR)DSS}$ ,  $V_{DD} = 80\%$   $V_{(BR)DSS}$

**Table 3. Thermal data**

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	1.14	$^\circ\text{C/W}$
$R_{thj-amb}^{(1)}$	Thermal resistance junction-amb max	42	$^\circ\text{C/W}$

1. When mounted on 1inch<sup>2</sup> FR-4 board, 2 oz Cu

## 2 Electrical characteristics

( $T_C = 25^\circ\text{C}$  unless otherwise specified)

**Table 4. On /off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$I_D = 1 \text{ mA}, V_{GS} = 0$	600			V
$I_{\text{DSS}}$	Zero gate voltage drain current ( $V_{GS} = 0$ )	$V_{DS} = 600 \text{ V}$			1	$\mu\text{A}$
		$V_{DS} = 600 \text{ V}, T_C = 125^\circ\text{C}$			100	$\mu\text{A}$
$I_{GSS}$	Gate-body leakage current ( $V_{DS} = 0$ )	$V_{GS} = \pm 25 \text{ V}$			$\pm 100$	nA
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2	3	4	V
$R_{DS(\text{on})}$	Static drain-source on resistance	$V_{GS} = 10 \text{ V}, I_D = 6 \text{ A}$		0.260	0.310	$\Omega$

**Table 5. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 50 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0$	-	1000	-	pF
$C_{oss}$	Output capacitance			60	-	pF
$C_{rss}$	Reverse transfer capacitance			3	-	pF
$C_{oss \text{ eq.}}^{(1)}$	Output equivalent capacitance	$V_{DS} = 0 \text{ to } 480 \text{ V}, V_{GS} = 0$	-	225	-	pF
$R_G$	Intrinsic gate resistance	$f = 1, I_D = 0$	-	3.5	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 480 \text{ V}, I_D = 12 \text{ A}, V_{GS} = 10 \text{ V}$ (see <a href="#">Figure 14</a> )	-	35	-	nC
$Q_{gs}$	Gate-source charge		-	6	-	nC
$Q_{gd}$	Gate-drain charge		-	20	-	nC

1.  $C_{oss \text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DS}$ .

**Table 6. Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300 \text{ V}, I_D = 6.5 \text{ A}, R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see <a href="#">Figure 17</a> )	-	12	-	ns
$t_r$	Rise time			15		ns
$t_{d(off)}$	Turn-on delay time			55		ns
$t_f$	Fall time			25		ns

**Table 7. Source drain diode**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current		-		12	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		48	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 12 \text{ A}, V_{GS} = 0$	-		1.6	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 12 \text{ A}, \text{di/dt} = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 60 \text{ V}$ (see <i>Figure 15</i> )	-	300		ns
$Q_{rr}$	Reverse recovery charge		-	4.0		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	25		A
$t_{rr}$	Reverse recovery time	$V_{DD} = 60 \text{ V}$ $\text{di/dt} = 100 \text{ A}/\mu\text{s}, I_{SD} = 12 \text{ A}$ $T_j=150^\circ\text{C}$ (see <i>Figure 15</i> )	-	360		ns
$Q_{rr}$	Reverse recovery charge		-	4.5		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	25		A

1. Pulse width limited by safe operating area.
2. Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

## 2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

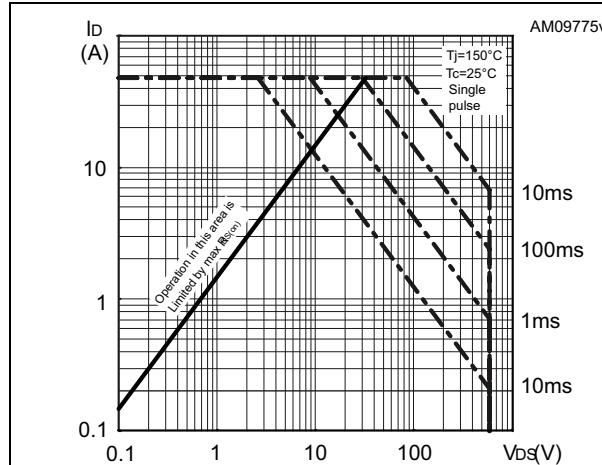


Figure 3. Thermal impedance

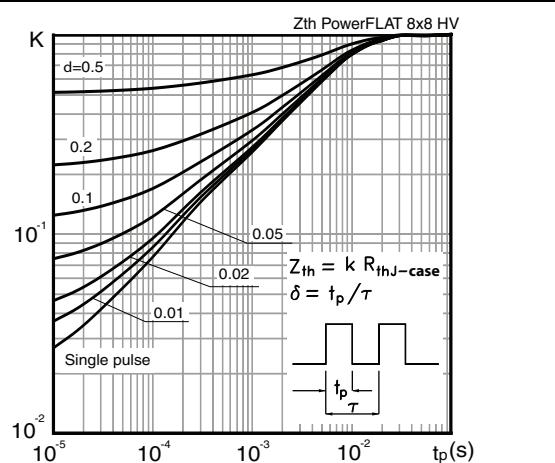


Figure 4. Output characteristics

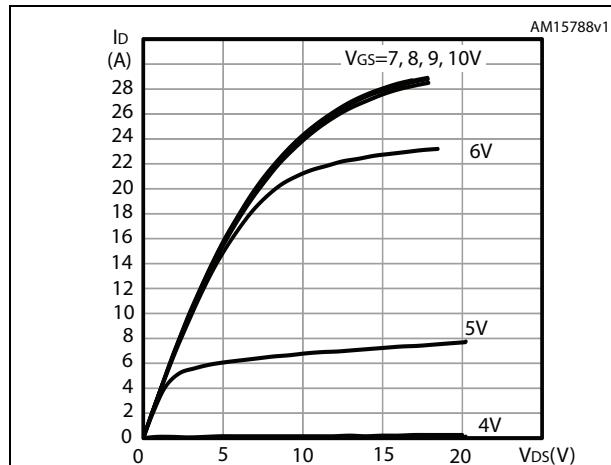


Figure 5. Transfer characteristics

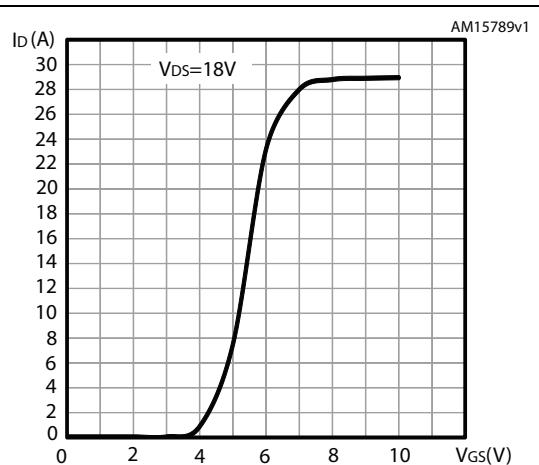
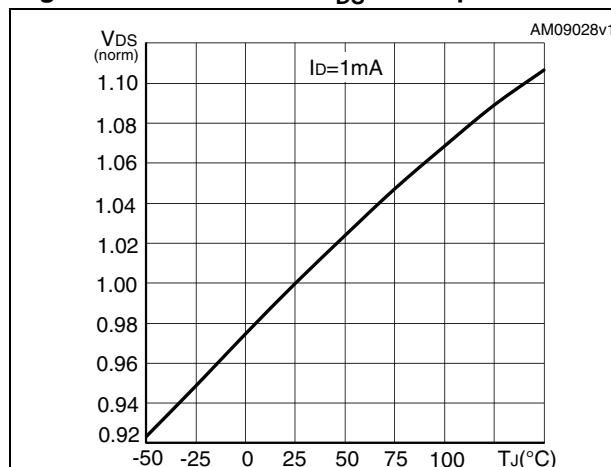
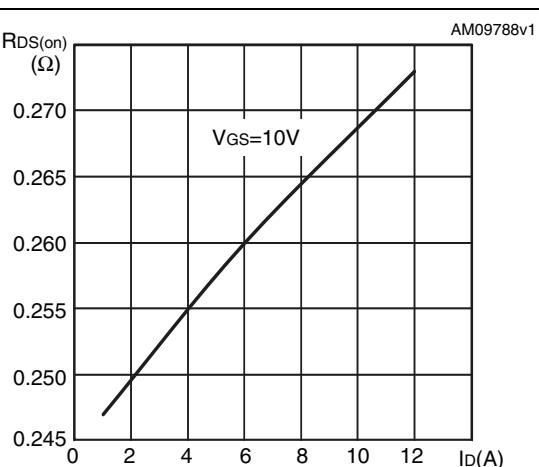
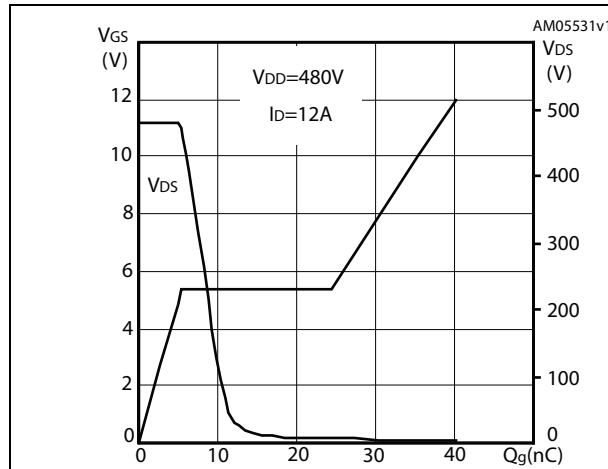
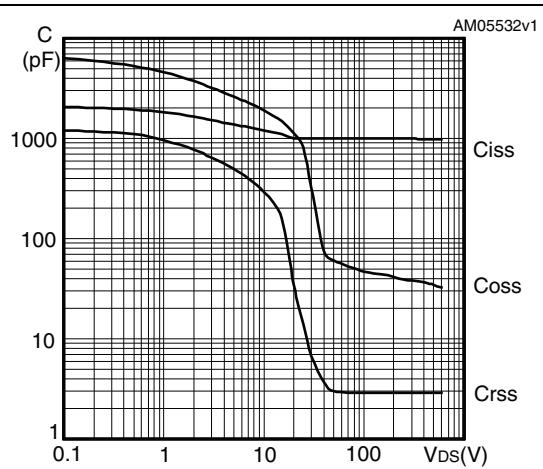
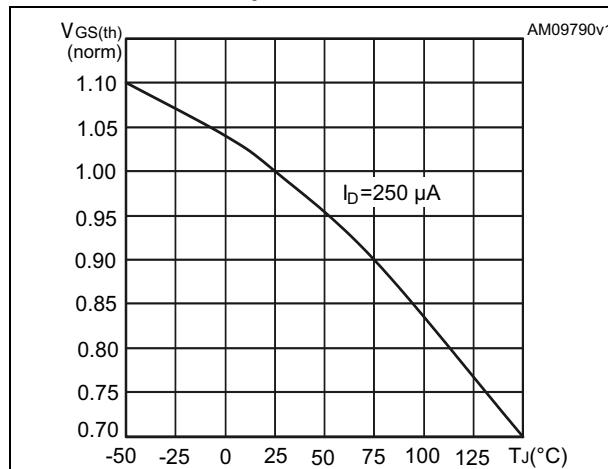
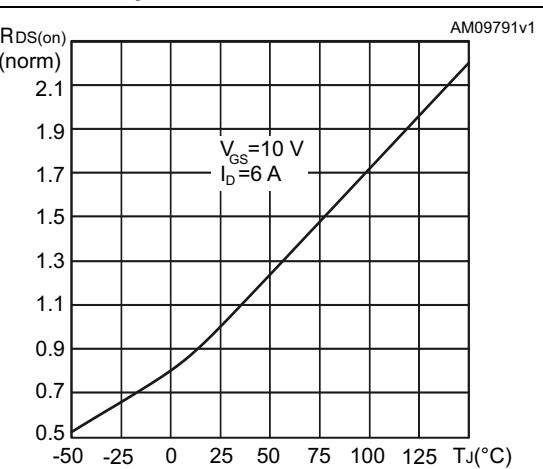
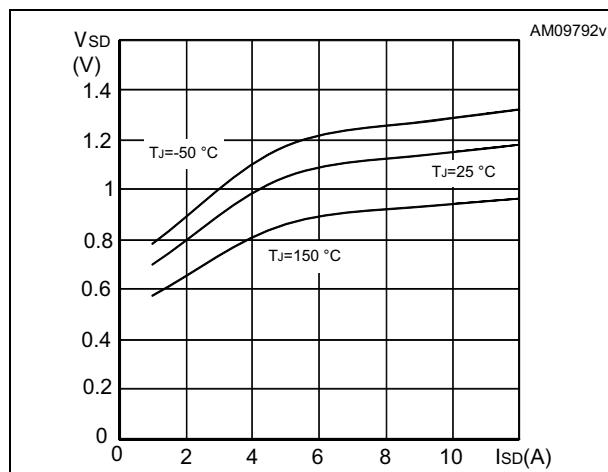
Figure 6. Normalized  $V_{DS}$  vs temperature

Figure 7. Static drain-source on-resistance



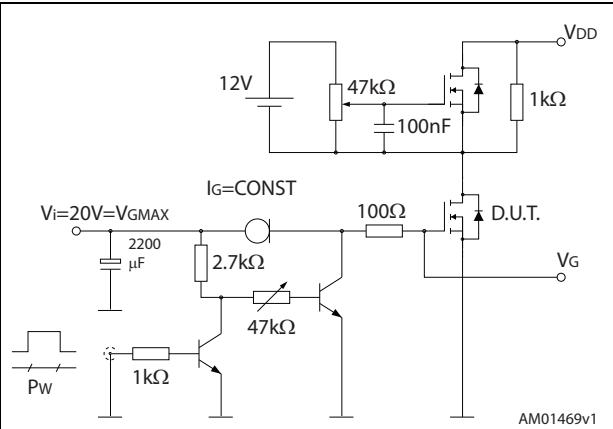
**Figure 8. Gate charge vs gate-source voltage****Figure 9. Capacitance variations****Figure 10. Normalized gate threshold voltage vs temperature****Figure 11. Normalized on-resistance vs temperature****Figure 12. Source-drain diode forward characteristics**

### 3 Test circuits

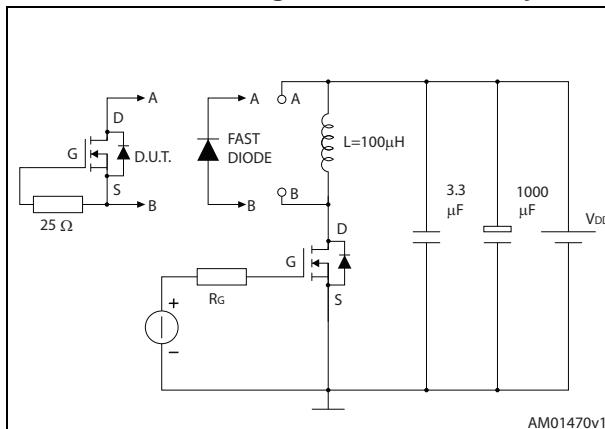
**Figure 13. Switching times test circuit for resistive load**



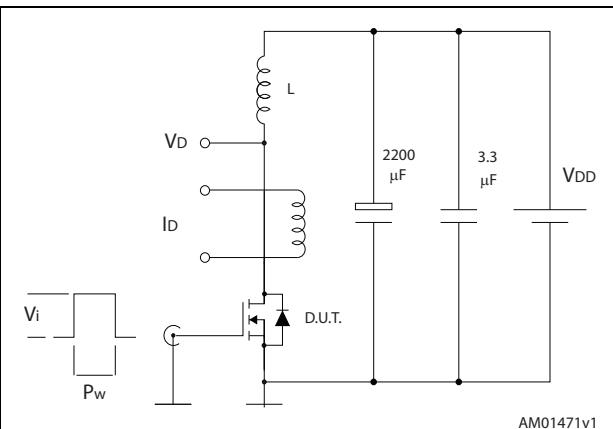
**Figure 14. Gate charge test circuit**



**Figure 15. Test circuit for inductive load switching and diode recovery times**



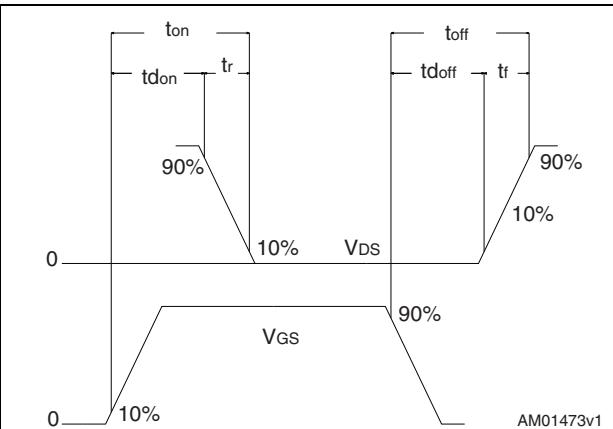
**Figure 16. Unclamped inductive load test circuit**



**Figure 17. Unclamped inductive waveform**



**Figure 18. Switching time waveform**

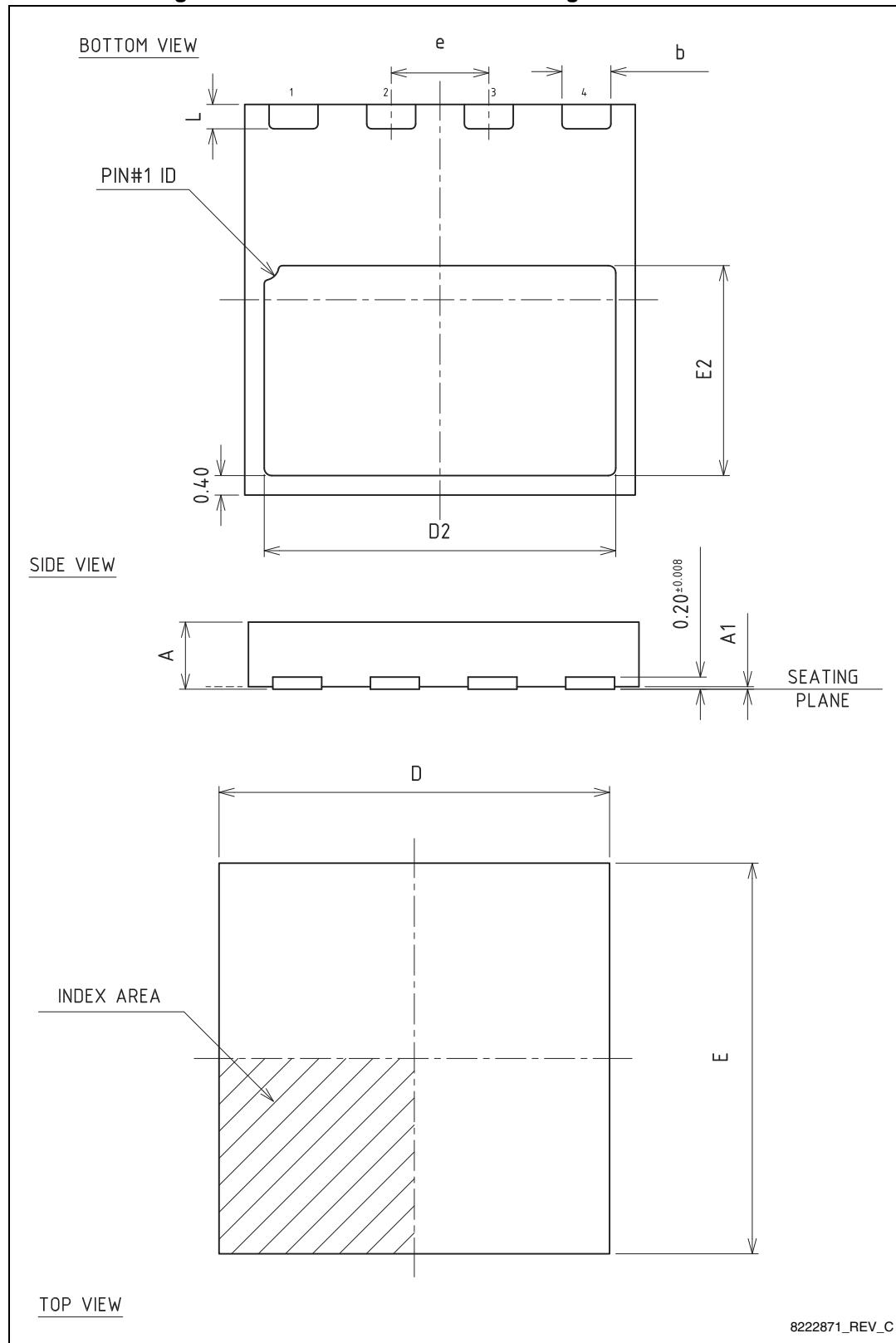


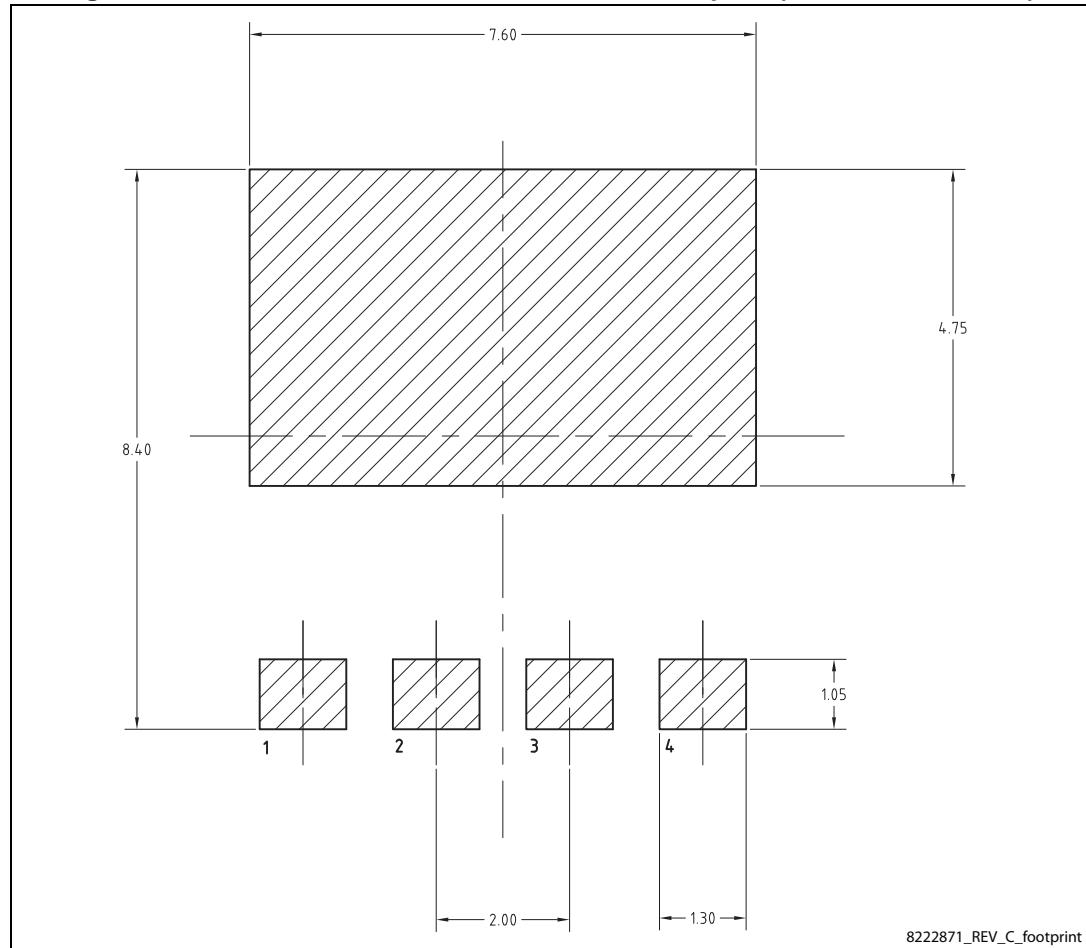
## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
ECOPACK® is an ST trademark.

**Table 8. PowerFLAT™ 8x8 HV mechanical data**

Dim.	mm		
	Min.	Typ.	Max.
A	0.80	0.90	1.00
A1	0.00	0.02	0.05
b	0.95	1.00	1.05
D		8.00	
E		8.00	
D2	7.05	7.20	7.30
E2	4.15	4.30	4.40
e		2.00	
L	0.40	0.50	0.60

**Figure 19. PowerFLAT™ 8x8 HV drawing mechanical data**

**Figure 20. PowerFLAT™ 8x8 HV recommended footprint (dimensions in mm.)**

## 5 Packaging mechanical data

Figure 21. PowerFLAT™ 8x8 HV tape

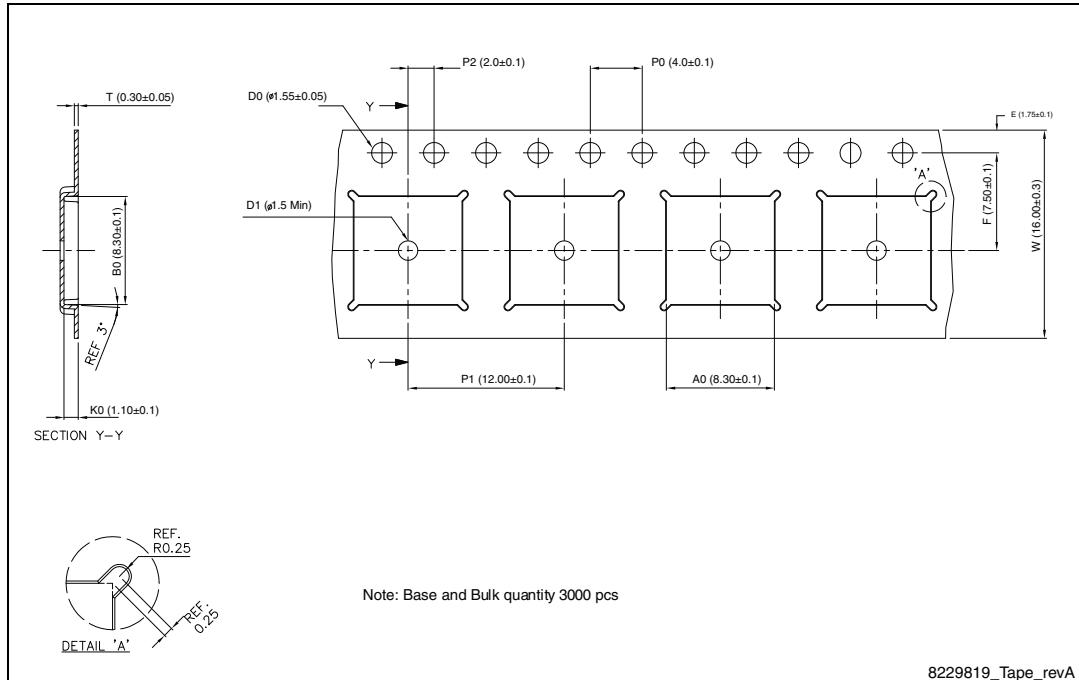


Figure 22. PowerFLAT™ 8x8 HV package orientation in carrier tape.

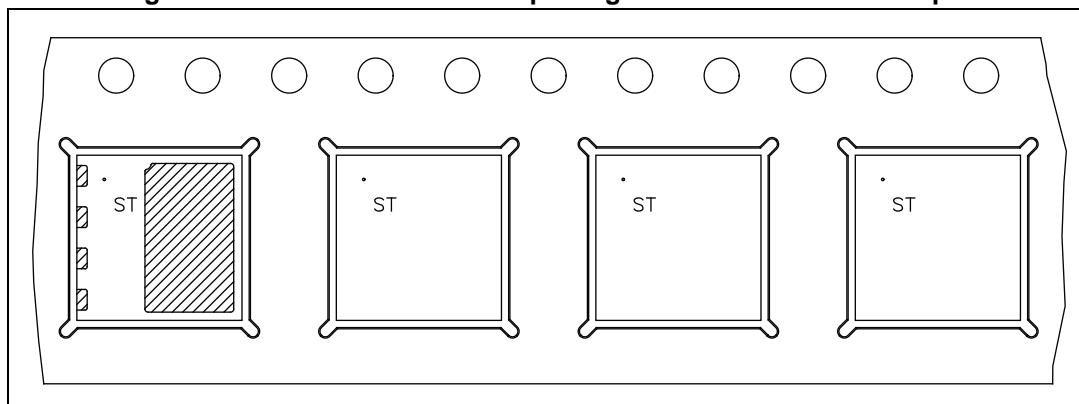
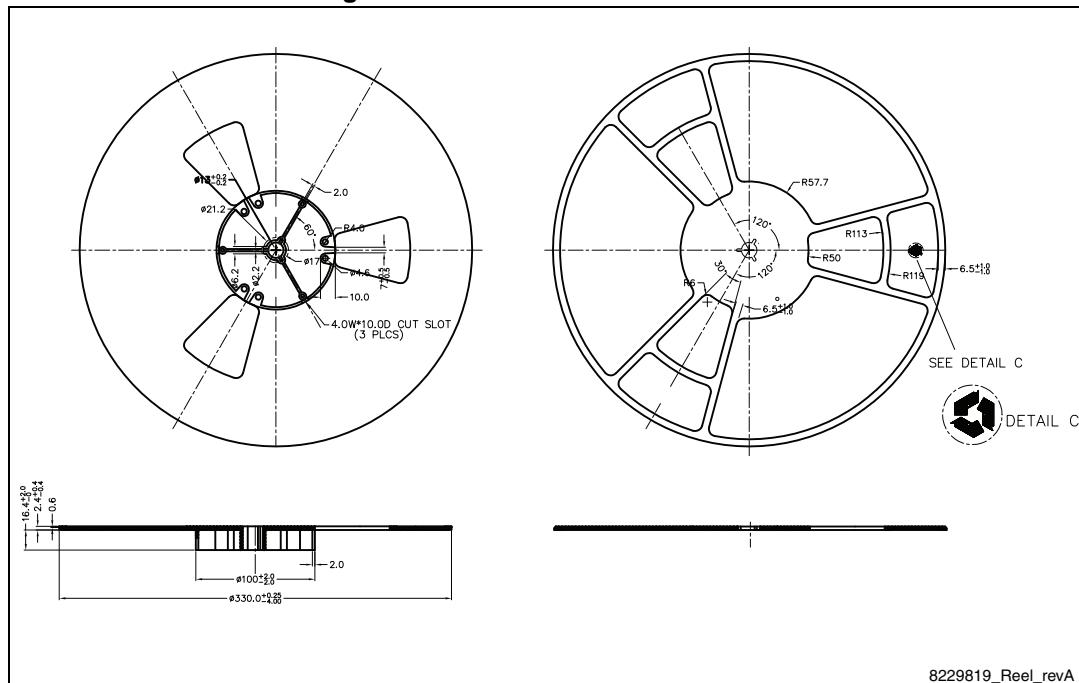


Figure 23. PowerFLAT™ 8x8 HV reel



## 6 Revision history

**Table 9. Document revision history**

Date	Revision	Changes
19-May-2011	1	First release.
03-Nov-2011	2	<i>Section 4: Package mechanical data</i> has been updated. Minor text changes.
28-Nov-2013	3	<ul style="list-style-type: none"><li>– Modified: title</li><li>– Modified: <math>V_{GS}</math>, <math>I_{AR}</math>, <math>E_{AS}</math> values in <i>Table 2</i></li><li>– Modified: note 2 in <i>Table 2</i></li><li>– Modified: <math>R_{thj\text{-amb}}</math> value in <i>Table 3</i></li><li>– Modified: <math>I_D</math> value in <i>Table 5</i></li><li>– Modified: the entire typical value in <i>Table 6</i></li><li>– Modified: <math>I_{SD}</math> value in <i>Table 6</i></li><li>– Modified: <i>Figure 3, 4, 5, 13, 14, 15, and 16</i></li><li>– Updated: <i>Section 4: Package mechanical data</i> and added <i>Section 5: Packaging mechanical data</i></li></ul>

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